



SWTEST

PROBE TODAY, FOR TOMORROW

2025 CONFERENCE

Ultra-low leakage probe card for wafer parametric testing enabled by μ 3D printing

 **EXADDON**

 **SYNERGIE CAD
GROUP**

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 - History:
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 - Method:
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- μ3D probe printing
- from innovation to industrialization
- ultra-low leakage probe card
- from simulation to test
- ultra-low leakage probe card
- pros and cons
- more than one solution
- more than ultra-low leakage

Recap: μ 3D probe printing



3D printing cantilever

Width: 1/3 of a human hair

3D printing nozzle

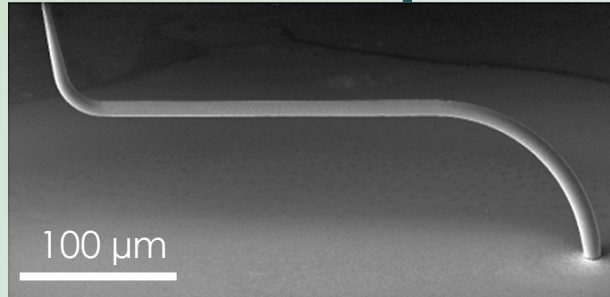
Opening 500nm

3D printable shape

“Any”. From cantilever to springs

Recap: μ 3D probe printing

3D scaffold printing



Diameter

From few to tens of microns
and tuneable along the probe

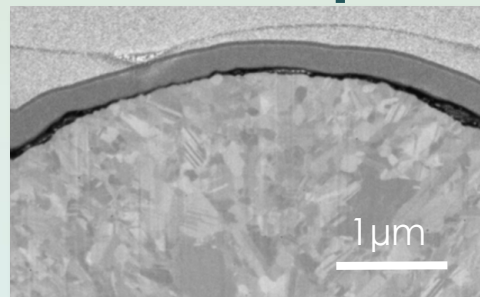
Length

From tens to hundreds of
microns

Shape

“Any”. From cantilever to
springs

Material quality



Material density

> 99%, homogeneous

Mechanical strength

Yield stress in line with cold
drawn copper

Electrical conductivity

> 87% of bulk copper

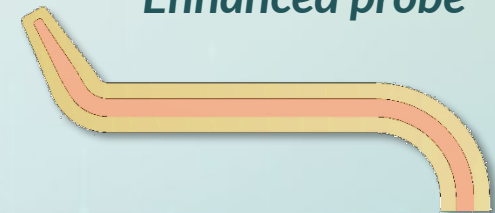
=> Pure copper metal

Tunability

Y Probe copper core

global electroplating

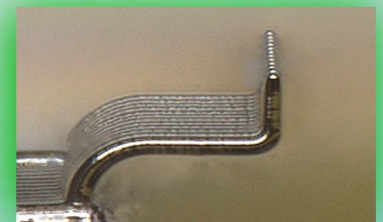
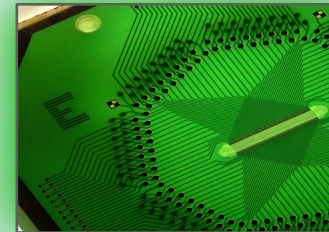
Enhanced probe



=> Adding metal shells
=> Tune stiffness & force
=> Contact resistance
=> Max. current

From innovation to industrialization

- 5500 B.C. Chalcolithic era (copper age)
- 2017 start of a new copper age, Exaddon micro metal object printing
 - Hardware and process development
 - Focus on scientific and R&D applications
- 2022 focus on semiconductor testing
- 2023 presenting first μ 3D printed probes
- 2024 μ LED wafer testing with 3D printed probes
- 2025 ultra-low leakage probe card with 3D printed probes
 - production ramp up μ LED & parametric testing

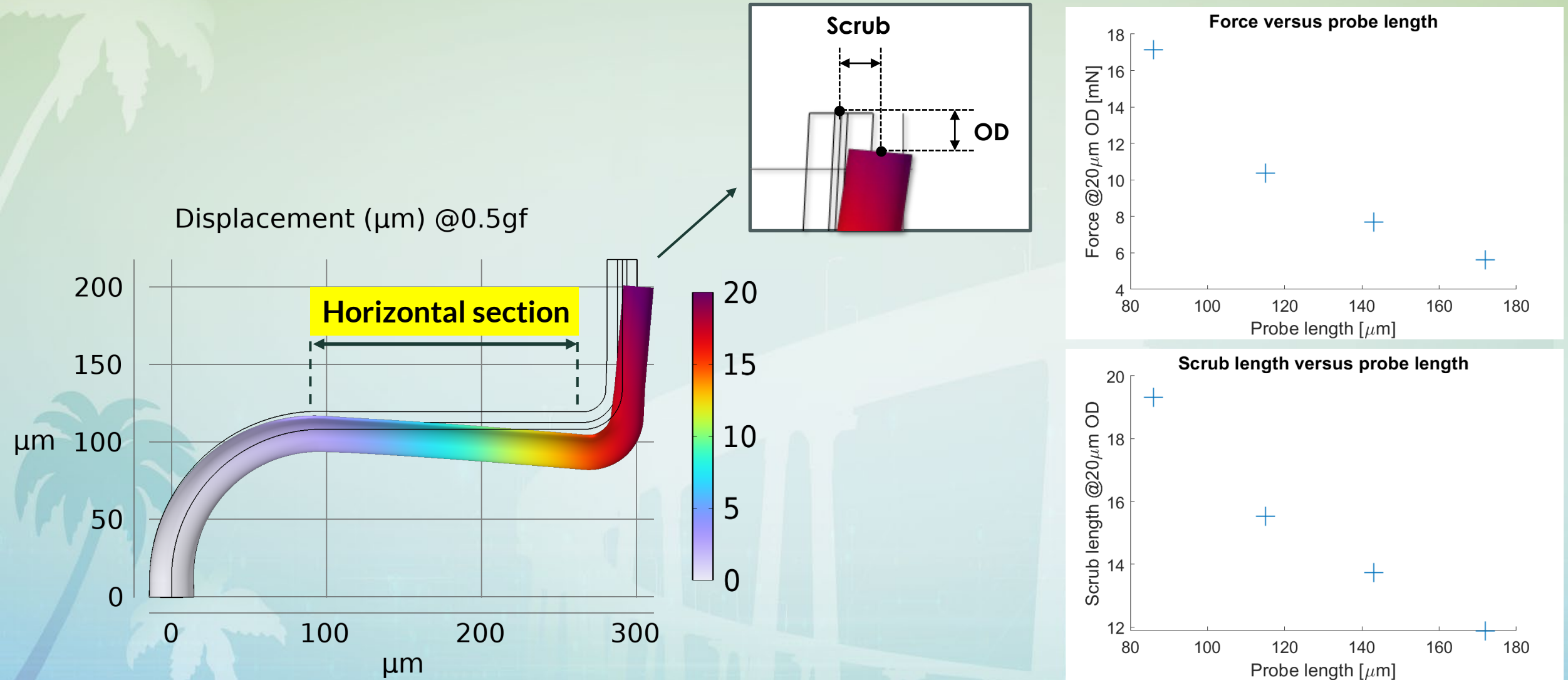


Goal: Ultra-low leakage probe card via μ 3D printing

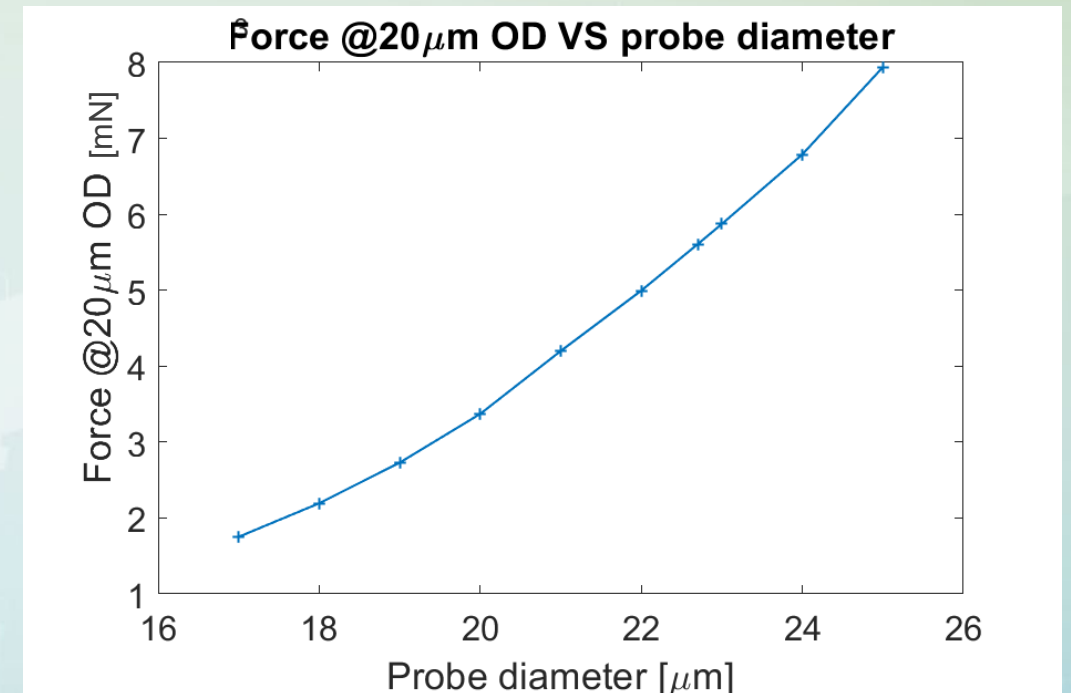
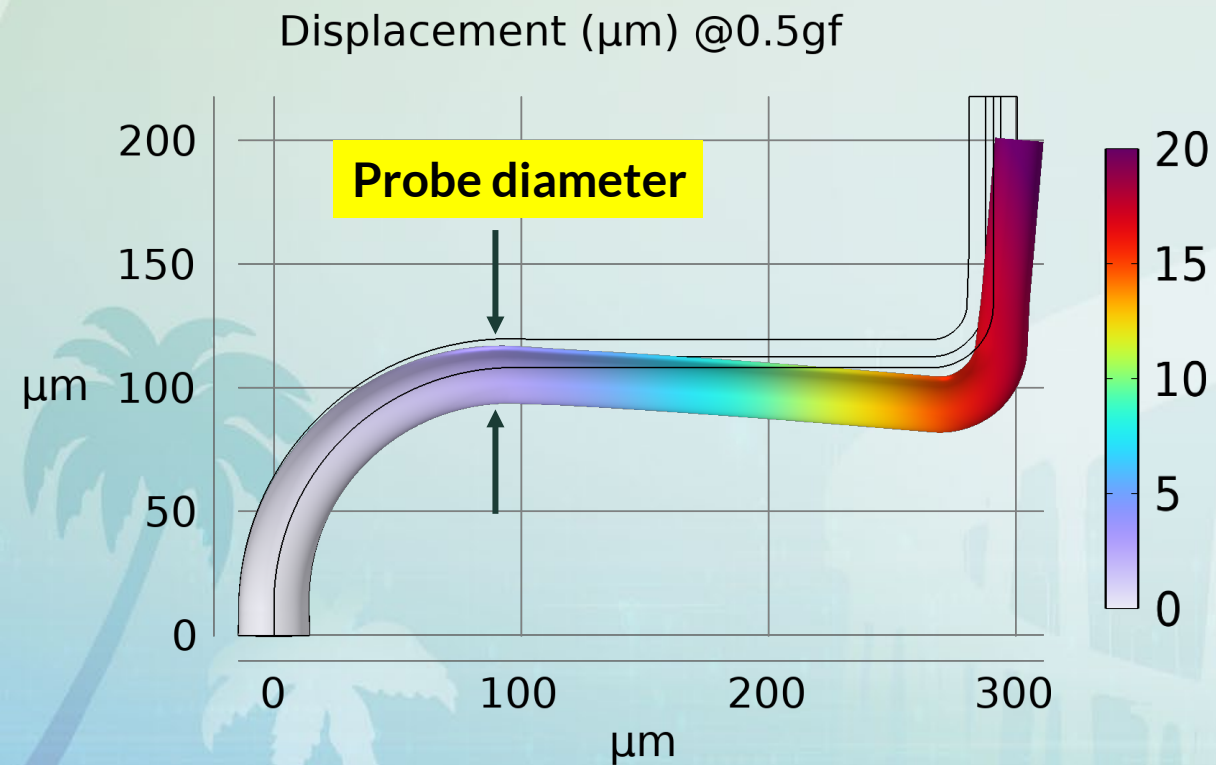
- Achieve background ultra-low leakage $< 1 \text{ fA/V}$
 - for sensitive applications (e.g., CMOS, MEMS)
 - Enable $30 \times 30 \mu\text{m}^2$ test pads through minimized scrub
 - Creating 50% less trench width, and reducing product cost
 - Introduce modular, replaceable (in minutes) probes
 - With precise force control to prevent pad / chip damage
- => Establish μ 3D printing as a scalable solution
- For advanced parametric probe cards

Simulation

Impact of the probe geometry



Impact of the probe diameter



The background of the slide features a light blue and green gradient. On the left side, there are three stylized palm trees in shades of green. In the center and right, there is a faint, semi-transparent image of a modern building with large glass windows and a curved facade.

DOE and Fabrication

Experimental validation - DOE

Fabrication

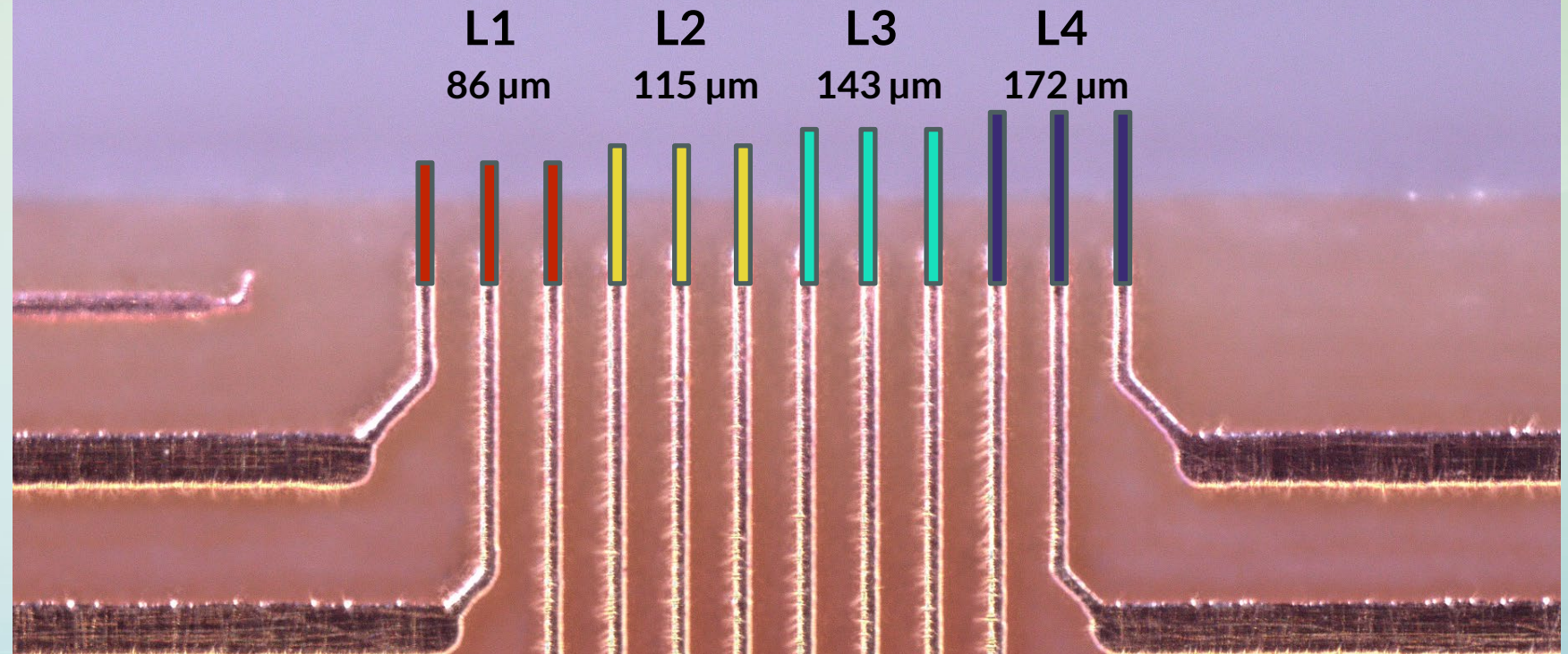
3D printed probe copper core

global electroplating

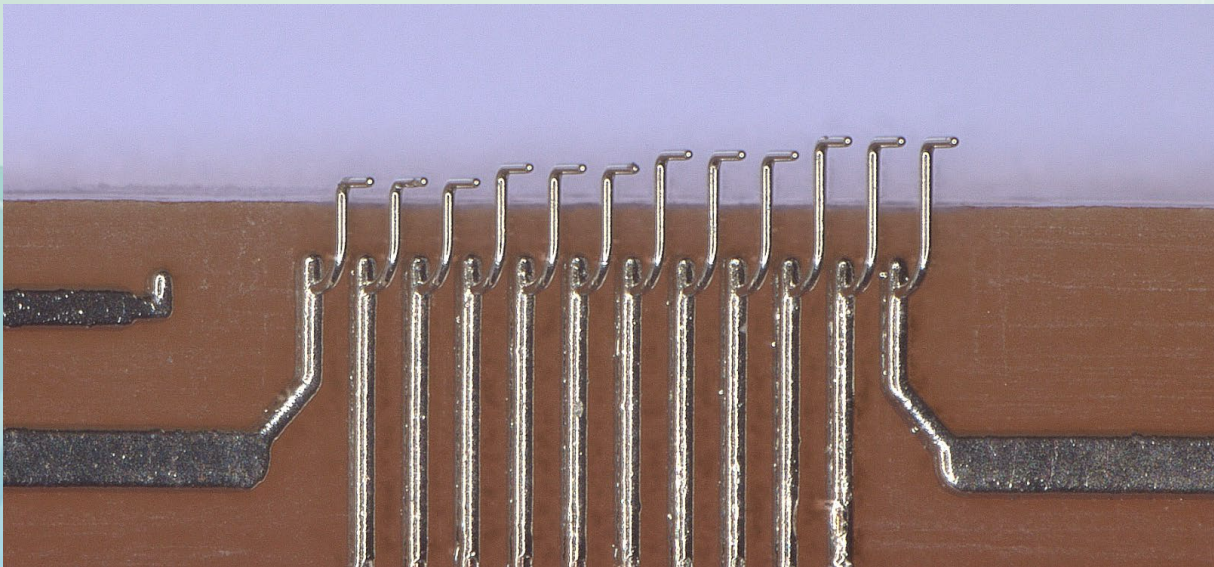
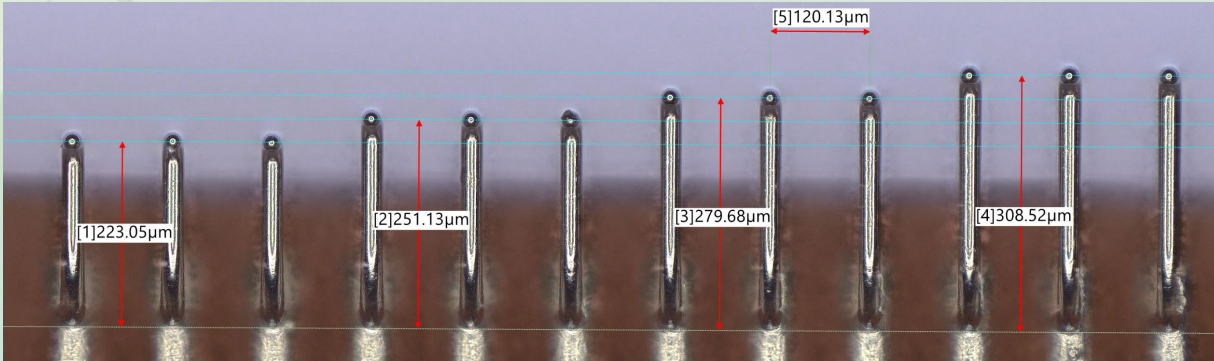
Final probe

Horizontal section

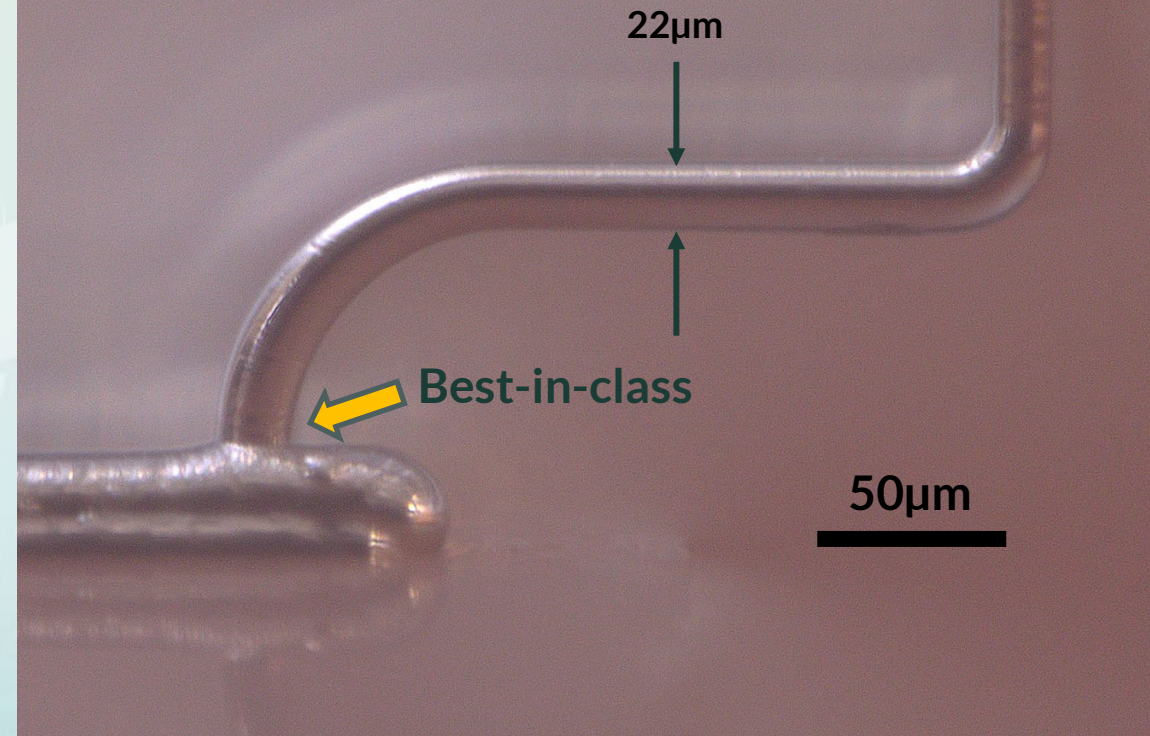
Testing 4 different horizontal lengths simultaneously on one substrate



Experimental validation - FAB



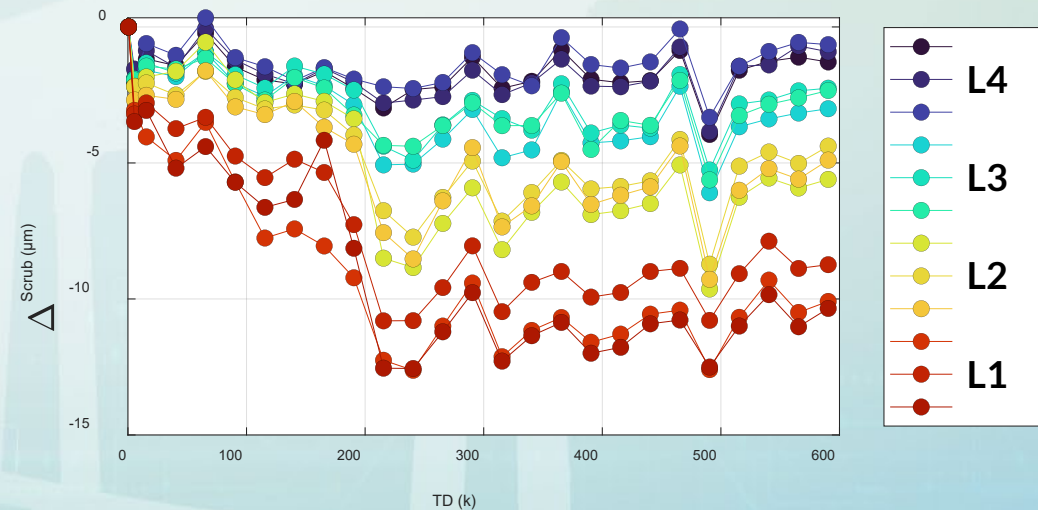
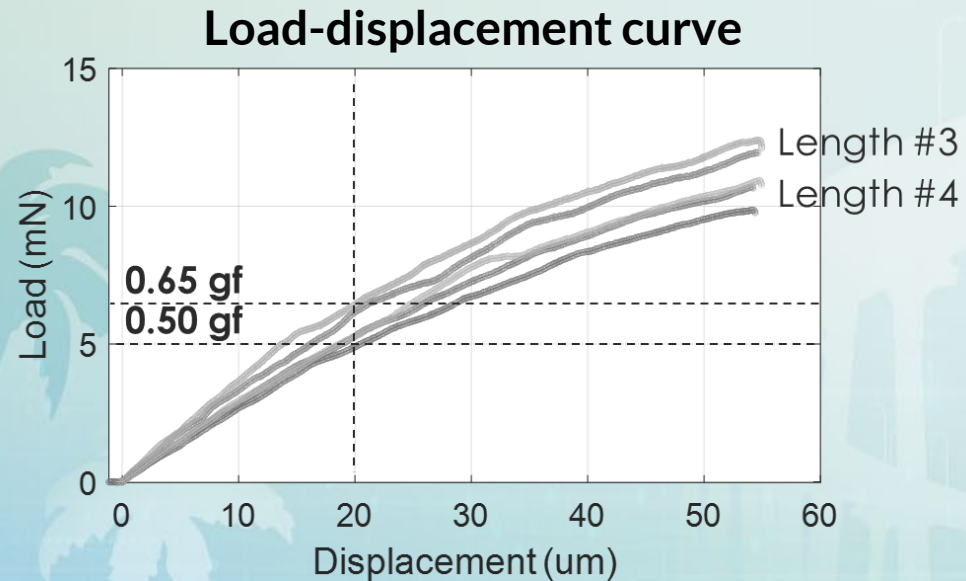
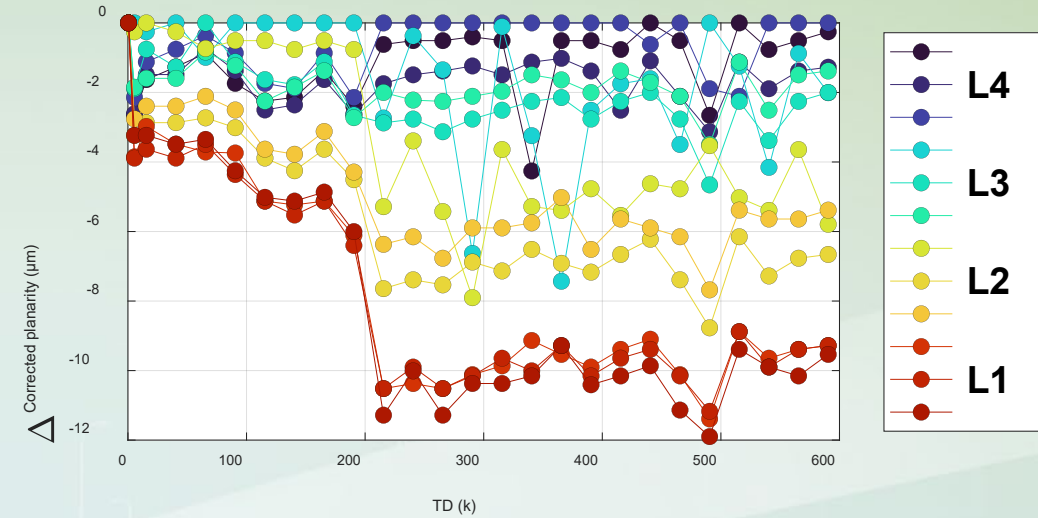
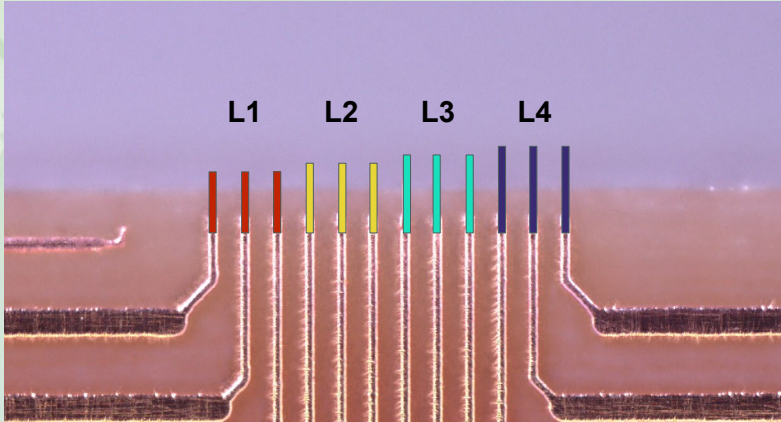
Side view of one of the fabricated probes printed directly onto the pre-patterned PCB





Testing

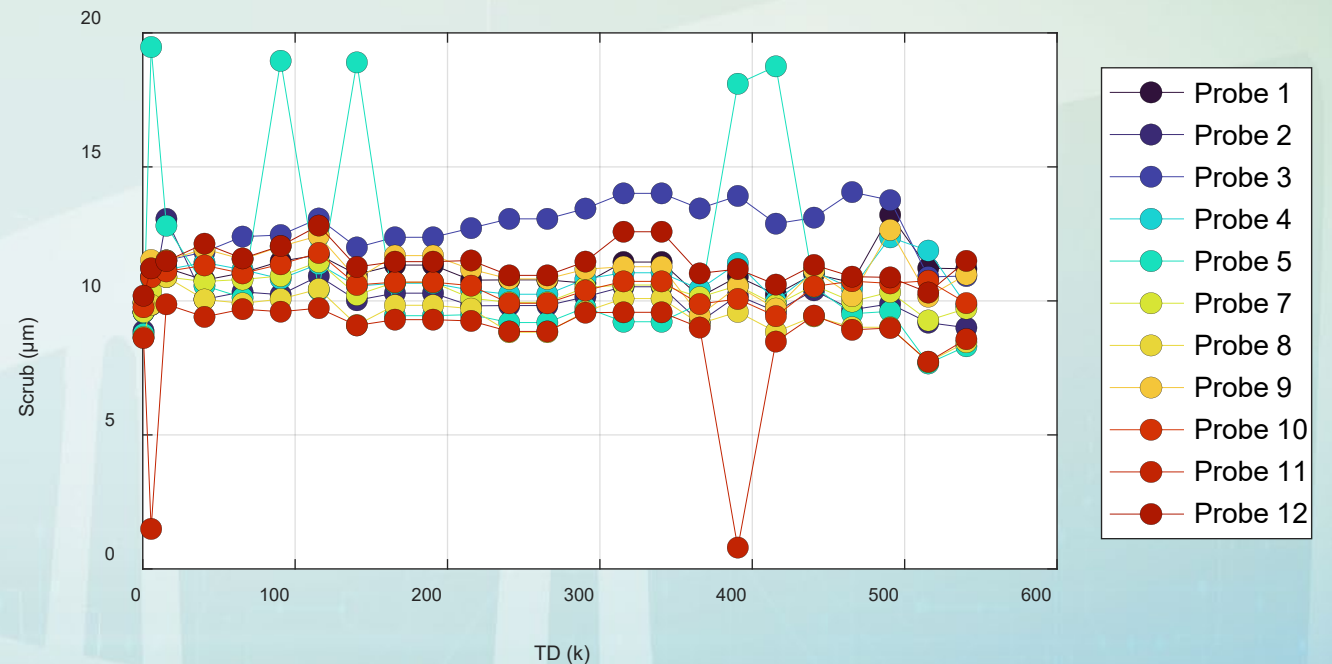
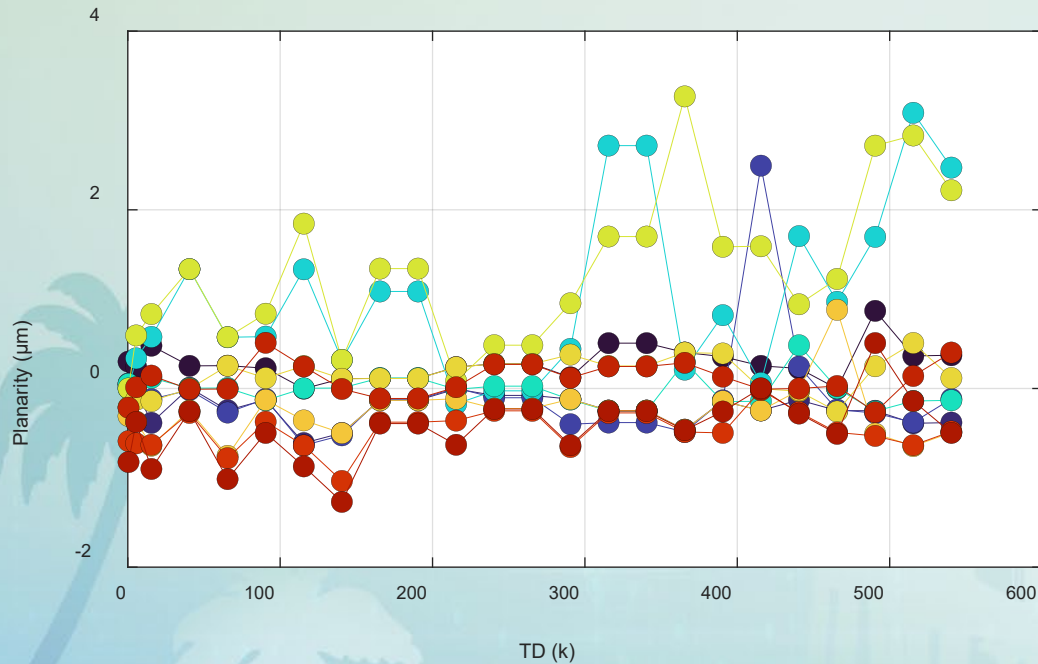
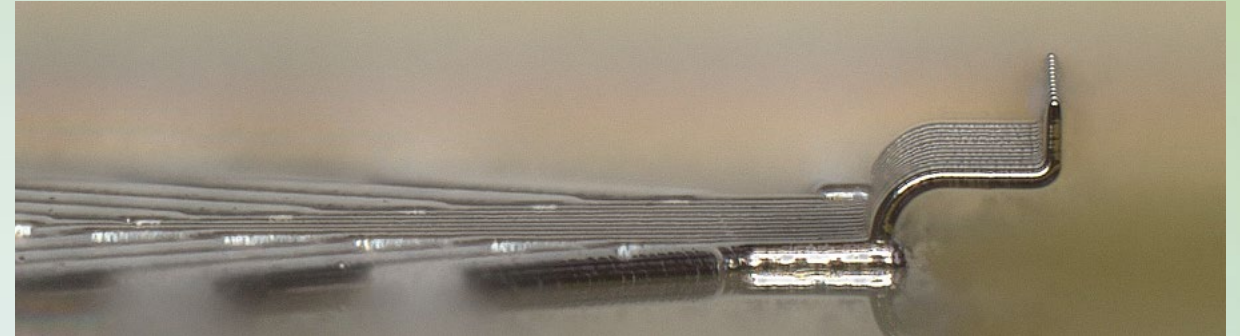
Results @20 μm OD



Validation and performances of L4 geometry

A new probe head with a set of L4 probes only has been manufactured and has put under test.

Results confirms that planarity, scrub length and tip shape are not significantly altered after 0.5M+ Touchdowns.

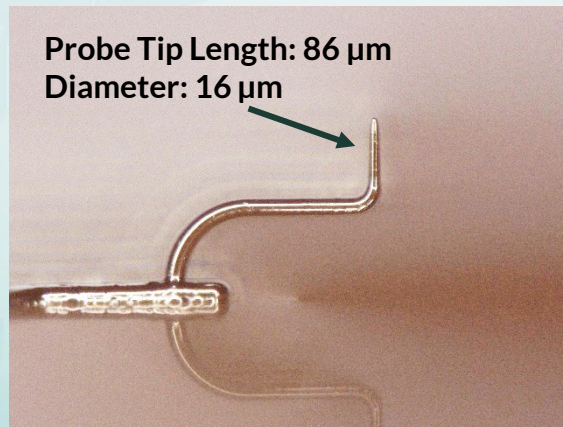
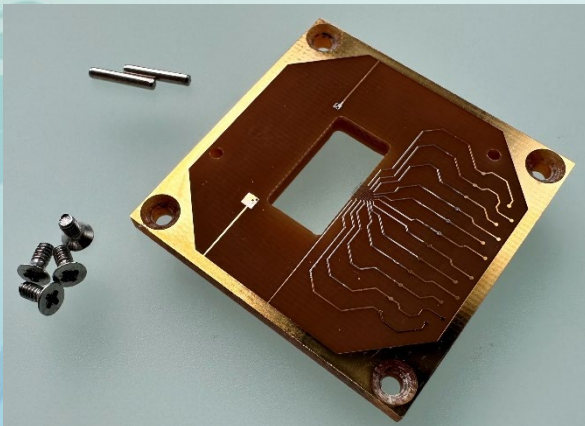
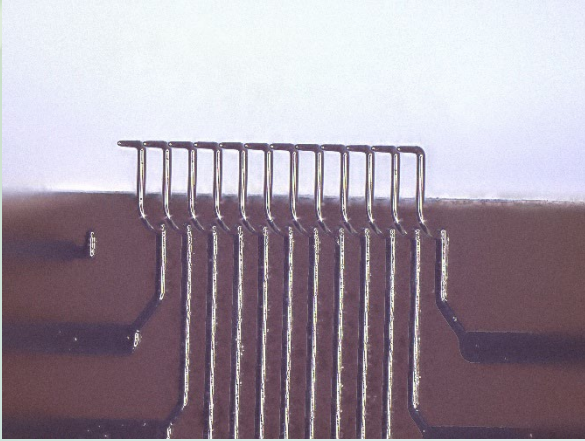


Fluctuations are due to errors in the measurements

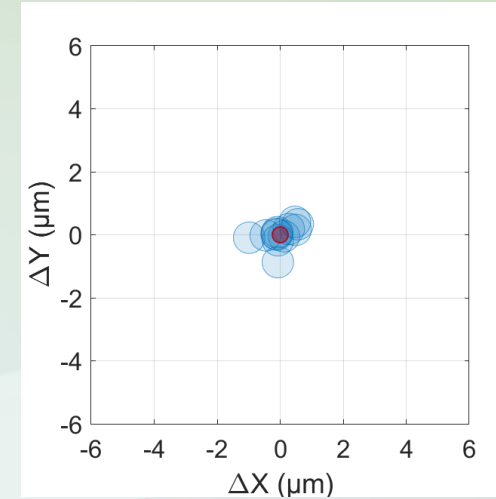
Parametric test Probe head

Final parametric test probe head characteristics:

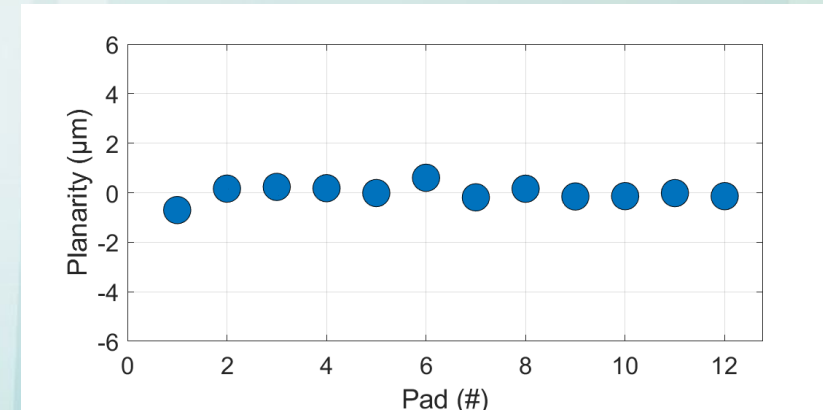
- State-of-the-art tip positioning accuracy
- Force @20 μm OD: 0.5-0.8 gf range
- Scrub length @20 μm OD: $\sim 10 \mu\text{m}$
- Lifetime > 0.5M TD (tested)
- Opening window for easy alignment
- Long and narrow tip designed to fit small pads and access deep trenches



Horizontal tip positioning (XY)



Vertical tip positioning (Z planarity)



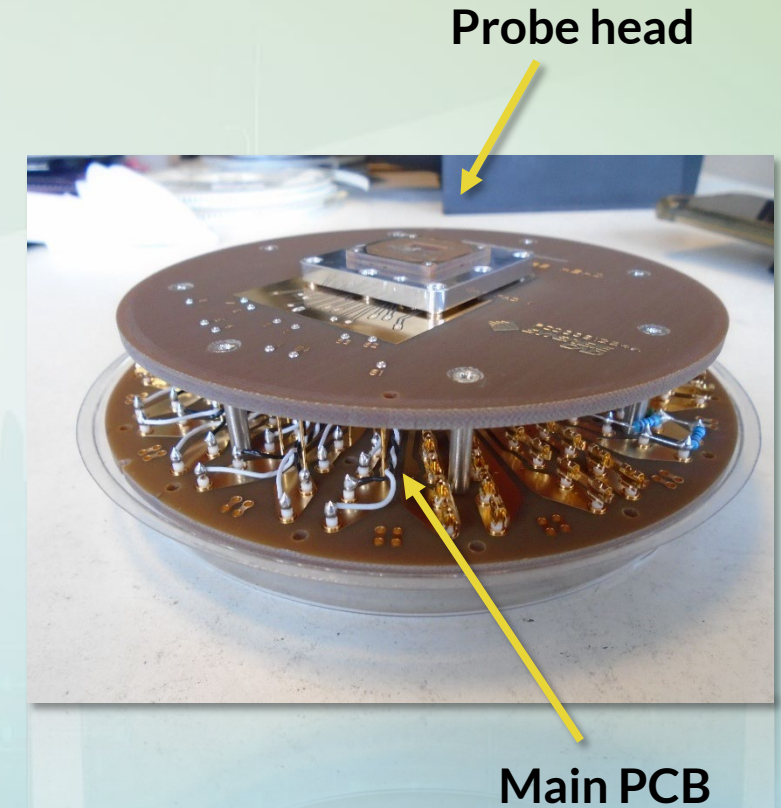
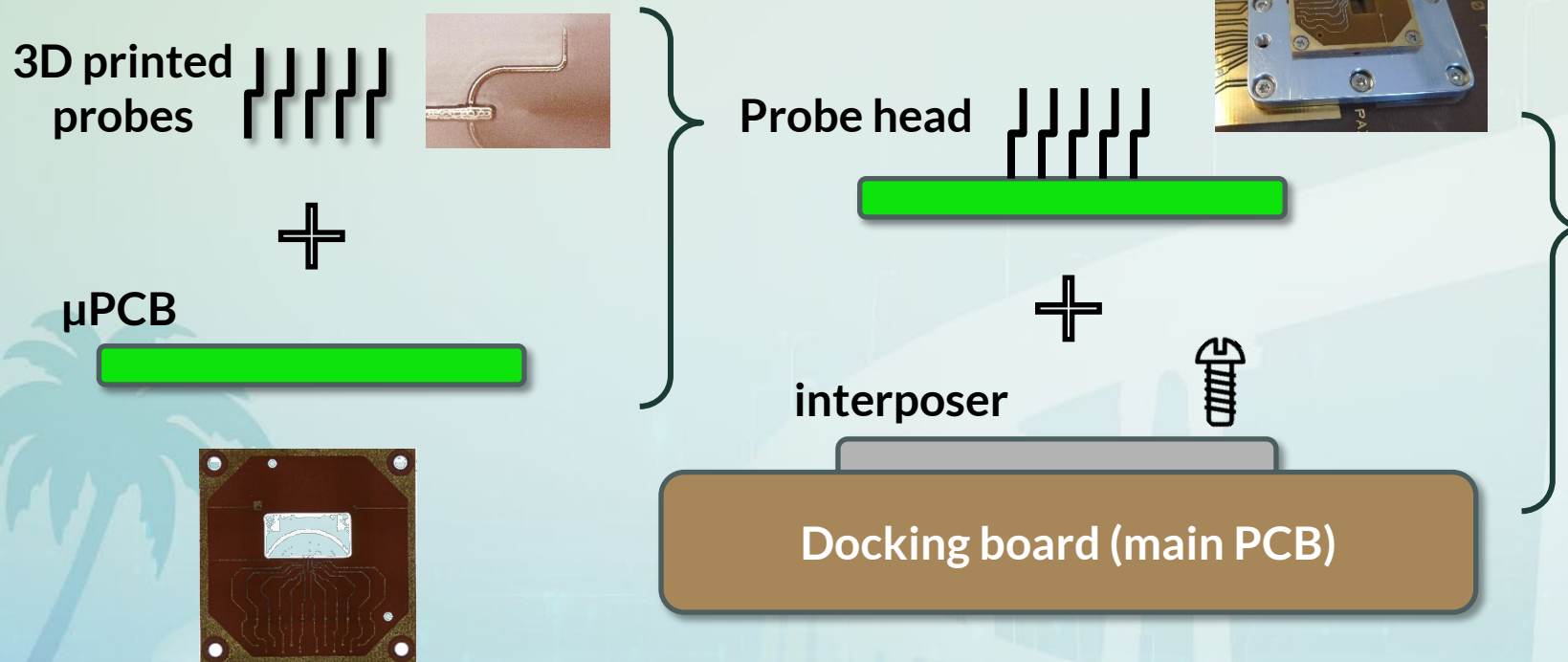
Modularity

Probe card - Modularity

Manufacturing the probe head
(3D printing probes onto μ PCB)

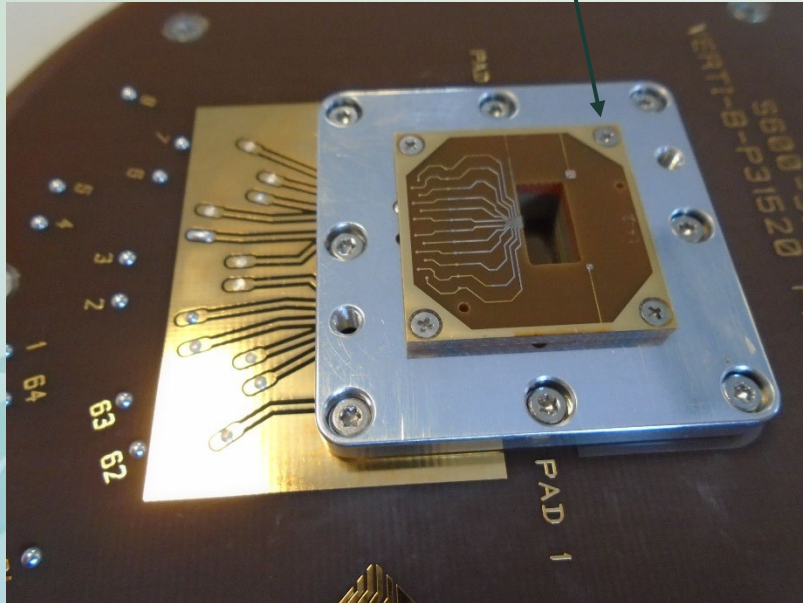
Assembling the probe head
(4 screws)

Full
assembly



Replaceability

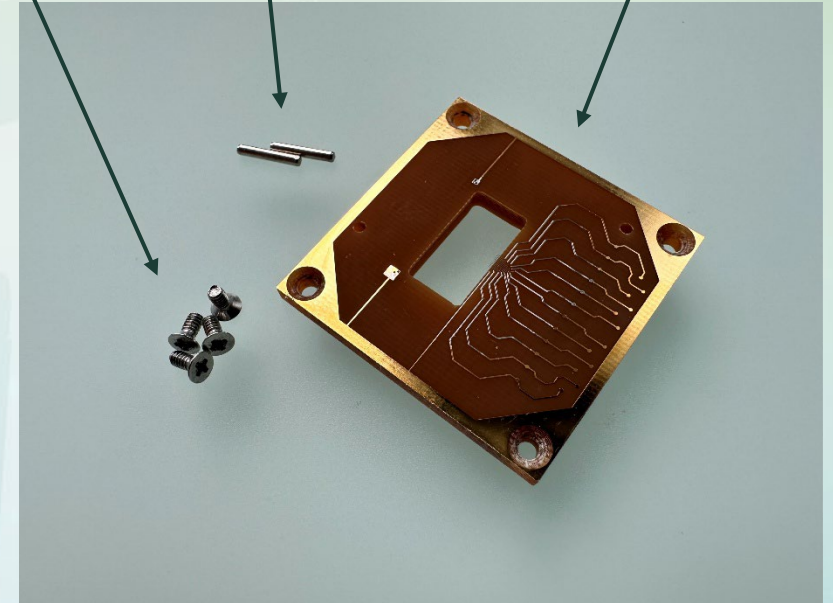
Screws x4



4 screws

2 locating pins

Probe head



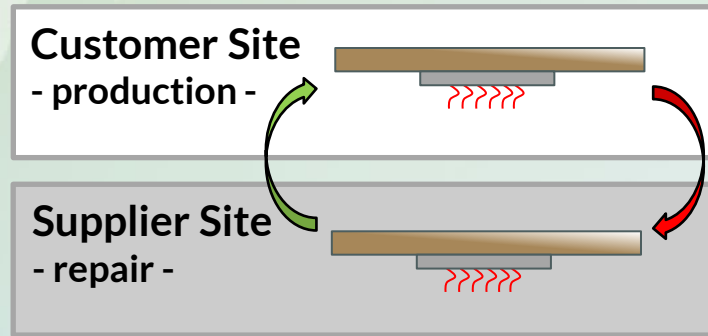
10 min

- Most efficient replacement
- Low cost, quick replacement
- No need for specifically specialized engineers

Compatible with *in-vacuum* or *inert atmosphere* storage

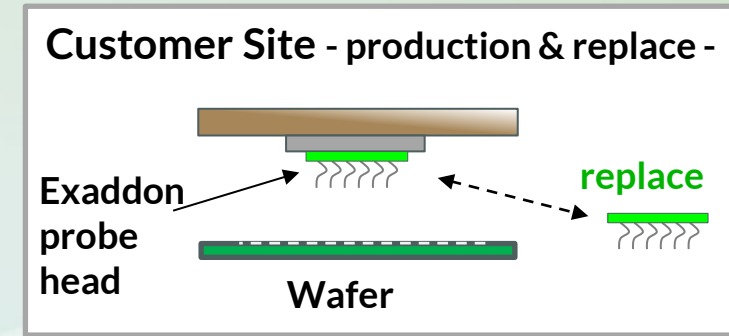
Probe card versatility

Traditional Probe Card Exchange



- ✗ Replace with twin probe card
- ✗ Redundant cards or long downtime
- ✗ Variable performance between cards
- ✗ High overhead (logistics, quality check)
- ✗ Bulky, difficult to storage: card tend to lose ultra-low leakage performances due to adsorbed water and contaminants

Exaddon Probe Head Exchange



- ✓ Quick, easy replacement process
- ✓ Lower CAPEX, near-zero downtime
- ✓ Consistent performance
- ✓ No overhead (logistics, quality check)
- ✓ Very compact, compatible with *in-vacuum* or inert atmosphere storage: retaining ultra-low leakage performances

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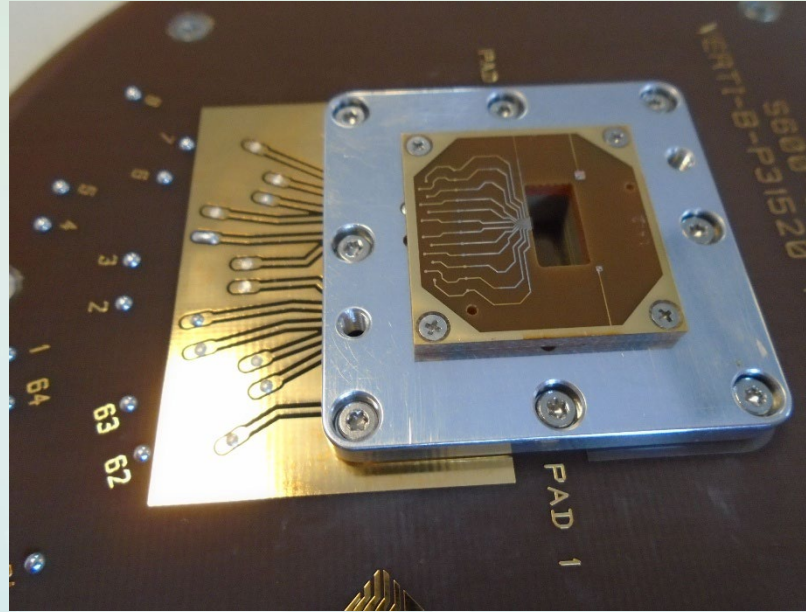
Ultra-low leakage

Tested ultra-low leakage performances



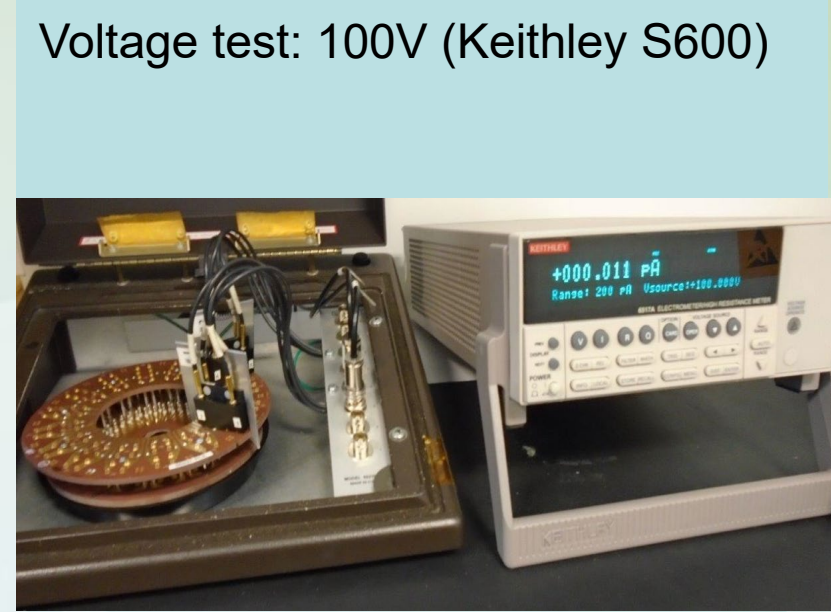
Docking board

Background current: **< 0.3 fA/V**



Docking board + μ PCB (no probes)

Background current: **< 0.7 fA/V**



Voltage test: 100V (Keithley S600)

Docking board + μ PCB + Probes

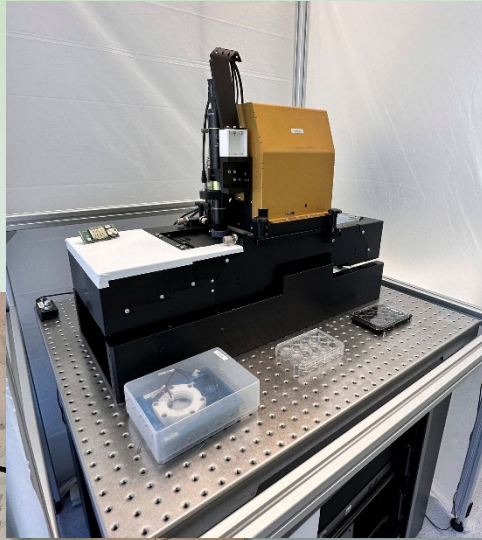
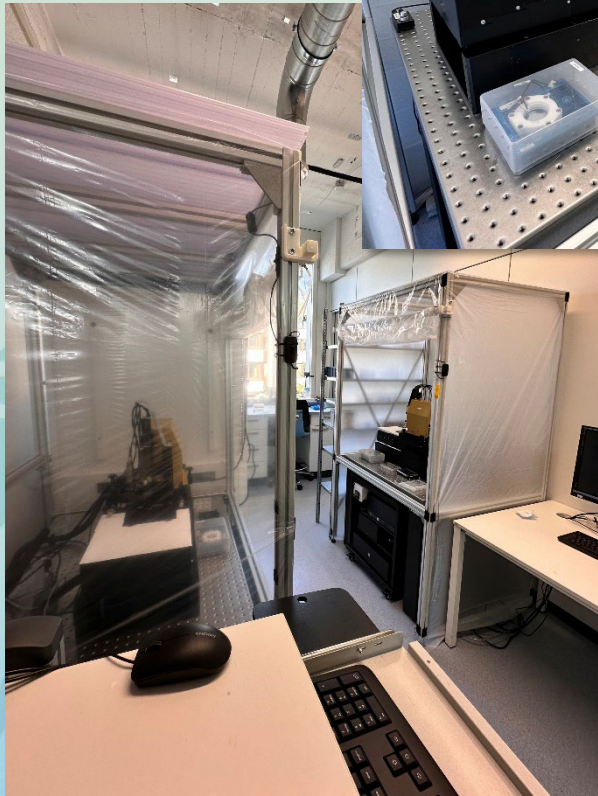
Background current: **< 0.8 fA/V**



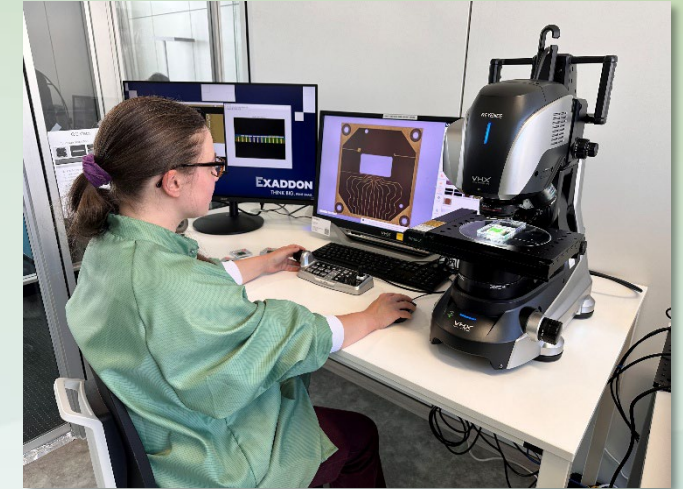
Scalability

Innovation Pilot Line

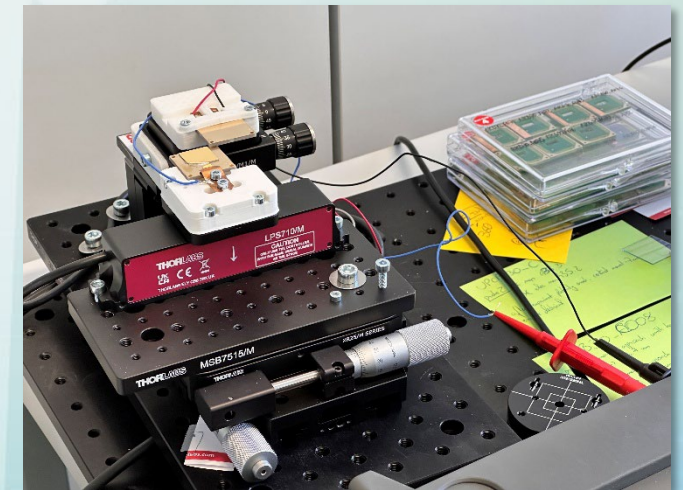
3D printers



Electroplating station



Quality control



Discussion

- **State-of-the-art probe tip positioning**
 - Due to 3D printer accuracy and print at place
- **State-of-the-art leakage performance, easy to maintain**
- **Modularity introduces an industry paradigm shift:**
 - From slow and costly repair to quick and convenient replacement
 - Changing test layouts within minutes
- **No single probe repair possible – is it really needed?**
 - Due to the manufacturing process, but also pitch and accuracy

Summary

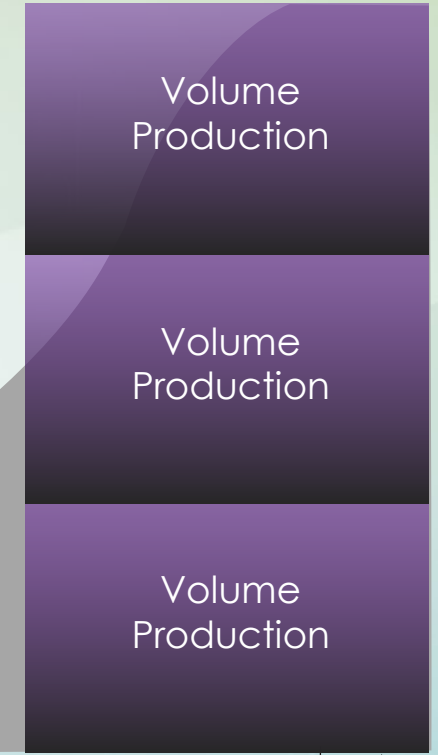
- Parametric Probe card
- Ultra-low leakage $< 1 \text{ fA/V}$
- Minimized scrub
- Modular concept
- Manufacturing ability

Follow-On work

- Next Gen. Parametric Probe Cards
 - More probes >12 and up to 64
 - New products (besides next-gen microLED)
- => Innovation ...
- => to Industrialization



today



> 2.5 years

Thank you!

For direct contact: Exaddon booth 304

For Investors and product
requests:



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